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Supplementary Information

Spontaneously Chiral Cubic Liquid Crystal: Three Interpenetrating Networks with a Twist

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S1. Previous models of the chiral bicontinuous cubic phase

Figure S1. Two previous models of the chiral bicontinuous cubic phase, both with space group $Im\overline{3}m$. (A) Model with three interpenetrating networks: inner (red), middle (yellow) and outer (blue) (Ref. S1). (B) Model with one infinite network and vesicles. The network is more or less the same as the middle network of Model A, but the inner and outer networks of Model A are replaced with vesicles (pink) at the corners and the body centre of the unit cell (Ref. S2).



S2. Structural models

Figure S2. Different views of the inner network.





Figure S3. Different views of the inner and outer networks.



Figure S4. Different views of the middle network





S3. Calculation of the structure factor *F*(*hkl*)

The structural factor *F*(*hkl*) is linked to the electron density $\rho(uvw)$, where *u*,*v*,*w* are the fractional coordinates in the unit cell, by Fourier transform

$$F(hkl) = \int_0^1 \int_0^1 \int_0^1 \rho(uvw) \exp[i2\pi(hu + kv + lw)] dudvdw \qquad (Equation S1)$$

F(hkl) is a complex number and has a real part, A(hkl) and an imaginary part, B(hkl)

$$F(hkl) = |F(hkl)|\exp[i\phi(hkl)] = A(hkl) + iB(hkl)$$
 (Equation S2)

Equation S1 can thus be rewritten as

$$A(hkl) = \int_0^1 \int_0^1 \int_0^1 \rho(uvw) \cos[2\pi(hu + kv + lw)] dudvdw \qquad (Equation S3a)$$
$$B(hkl) = \int_0^1 \int_0^1 \int_0^1 \rho(uvw) \sin[2\pi(hu + kv + lw)] dudvdw \qquad (Equation S3b)$$

Using the above equations, we have calculated the diffraction intensities and phases for each observed peak from the Fourier transform of the model, where the electron density of a point
$$\rho(uvw)$$
 in the unit cell is taken to be 1 when its distance to the nearest network segment is less than a constant value R, and 0 otherwise. The R constant defines the boundary between high and low electron density regions of the phase, and it is chosen to be $0.09a$ so that the high electron density regions occupy 45% of the total volume, where 45% is the volume ratio of the rigid aromatic core of the compound under study (compound 1e, ref. S3). The unit cell is divided in all three dimensions by 200 times, and the integration is approximated by summation

$$A(hkl) = \frac{C}{8000000} \sum_{u=0.005}^{1} \sum_{v=0.005}^{1} \sum_{w=0.005}^{1} \rho(uvw) \cos[2\pi(hu + kv + lw)] \qquad (Equation S4a)$$

$$B(hkl) = \frac{C}{8000000} \sum_{u=0.005} \sum_{v=0.005} \sum_{w=0.005} \rho(uvw) \sin[2\pi(hu + kv + lw)] \qquad (Equation S4b)$$

Here C=250 is a constant used so that the calculated values are more tractable. The calculated A(hkl) and B(hkl) values, relative intensities $I(hkl) = |F(hkl)|^2 = A(hkl)^2 + B(hkl)^2$, and phase angles $\phi(hkl)$ are shown in Table S1. In reconstruction of electron density map from experimental data, the phase angles, and the intensity ratios I(hkl)/I(hlk) are taken to be the same as calculated.

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(hkl)	A(hkl)	B(hkl)	I(hkl)	ф(hkl)
(110)	2.92	0.00	8.5	0
(200)	-9.38	0.00	88.0	π
(211)	-4.96	-0.52	24.8	-0.97π
(220)	1.80	0.00	3.3	0
(310)	0.85	0.00	0.7	0
(301)	6.40	0.00	41.0	0
(222)	4.08	-3.79	31.1	-0.24π
(321)	-8.00	-2.23	69.0	-0.91π
(312)	-3.46	-11.85	152.3	-0.59π
(400)	11.59	0.00	134.3	0
(411)	-5.76	-3.86	48.1	-0.81π
(330)	7.27	0.00	52.9	0
(420)	6.19	0.00	38.4	0
(402)	0.71	0.00	0.5	π
(332)	-0.71	2.72	7.9	0.58π
(422)	-0.68	-1.24	2.0	-0.66π

Table S1. Calculated intensities and phase angles of diffraction peaks of the *I*23 phase.

References

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S3. C. Dressel, F. Liu, M. Prehm, X. B. Zeng, G. Ungar and C. Tschierske, *Angew. Chem. Int. Ed.*, 2014, **126**, 13331-13336.